

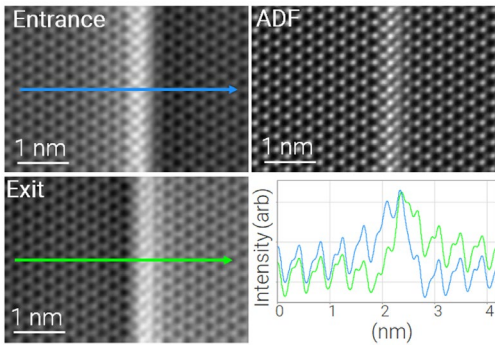
ELECTRON MICROSCOPY

# Atomic Resolution Imaging With Secondary Electrons

Tools for Tomorrow™



## Resolve out-of-plane structure with atomic resolution



## Dual SE detectors above and below sample

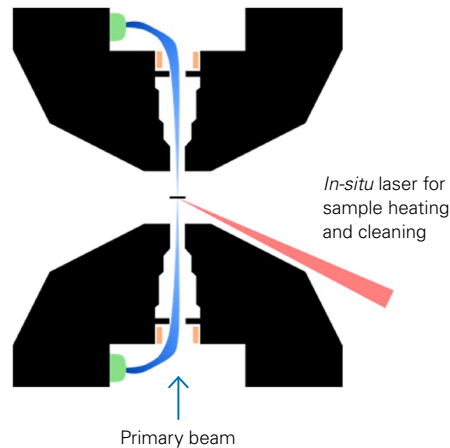


Figure 1 (left column)

MoS<sub>2</sub> monolayer line defect with out-of-plane structure causing inverted contrast in entrance and exit SE signals.

Figure 2

Schematic of dual secondary electron (SE) detectors above and below the sample.

## Monolayer surface sensitivity

- SE imaging is compatible with all STEM channels
- Laser for in-situ sample heating and cleaning
- Image entrance surface of bulk samples
- Atomic scale topographic information

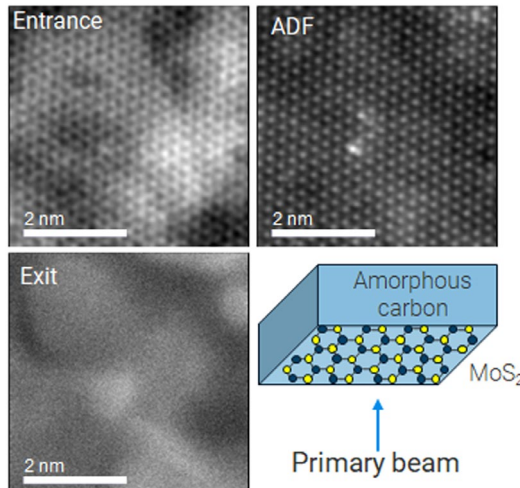


Figure 3

MoS<sub>2</sub> monolayer on a carbon film visible in the entrance but not the exit SE signal, demonstrating the ability to image Å scale features on the surface of a bulk sample.

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